

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/604,605	LEMAITRE ET AL.	
Examiner	Art Unit	
Tuyet Vo	2821	

SEARCHED						
Class	Subclass	Date	Examiner			
378	138	6/8/2005	TV			
	136					
	121					
	119	·				
,	129					
	140	,				
315	169.4		→			
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
378	138	6/8/2005	TV			
	136,121					
1	140	\	1			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
electrode/cathode/filament, beam/x-ray deflect/reflect/adjust focal/focus spot/location/poiint,	6/8/2005	TV		
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